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Application/Control No.	Applicant(s)/Patent under Reexamination
10/664,740	YALOVSKY ET AL.
Examiner	Art Unit
Maikhanh Nguyen	2176

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	530	2/14/2006	МК
715	526	2/14/2006	МК
709	219,229	2/14/2006	MK
Updated	Search	10/6/2006	MK
Updated	Search	6/27/2007	MK
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Name Search	2/14/2006	
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	2/14/2006	МК
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	10/6/2006	МК
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	6/27/2007	МК